



PTO/SB/08A (10-01)  
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Substitute for form 1449A/PTO		<b>Complete if Known</b>	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (use as many sheets as necessary)		Application Number	10/627,155
		Filing Date	7/24/03
		First Named Inventor	Patel
		Art Unit	<del>Not Yet Assigned</del> 2813
		Examiner Name	Not Yet Assigned
Sheet 1 of 6	Attorney Docket Number	P102-US	

U.S. PATENT DOCUMENTS					
Examiner Initials	Cite No. 1	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number - Kind Code <sup>2</sup> (if known)			
SW		US- 3,511,727	05-12-1970	Hays, R.G.	
SW		US- 4,190,488	02-26-1980	Winters, H.F.	
SW		US- 4,310,380	12-12-1982	Fiamm et al.	
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SW		US- 6,051,503	04-18-2000	Bhardwai, J.K.	
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SW		US- 6,355,181 B1	03-12-2002	McQuarrie, A.D.	
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SW		US- 2003/0166342 A1	09/04/03	Chinn, et al.	

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		Country Code 3 - Number 4 - Kind Code 5 (if known)				
SW		EP-0704884-A2	04-03-1996	Mehta, J.		
SW		EP-0822582-A2	02-04-1998	Bhardwaj, J.K.		
SW		EP-0822584-A2	04-04-1998	Bhardwaj, J.K.		
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SW		EP-0878824-A2	11-18-1998	McQuarrie et al.		
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SW		JP-1982/57098679-A	06-18-1982	Tsunetoshi, A.	Abstract	
SW		JP-1983/58130529-A	08-04-1983	Yoshihiro et al.	Abstract	
SW		JP-1985/60057938-A	04-03-1985	Katsumi et al.	Abstract	
SW		WO-98/32163	07-23-1998	Tai et al.		

Examiner Signature	<i>Stephen W. Smoot</i>	Date Considered	June 20, 2005
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		Number - Kind Code 2 (if known)			
W.S.		US- 6,409,876 B1	06-25-2002	McQuarrie, et al.	
W.S.		US- 6,396,619 B1	05-28-2002	Huibers, et al.	
W.S.		US- 6,576,489 B2	06/10/03	Leung, et al.	
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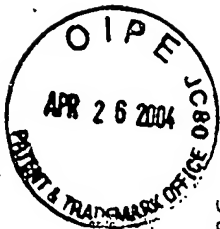
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		Country Code <sup>3</sup> - Number <sup>4</sup> - Kind Code <sup>5</sup> (if known)				
W.S.		JP-1997/09251981-A	09-22-1997	Kazuaki et al.	Abstract	
W.S.		JP-1998/10313128-A	11-24-1998	Hanmin et al.	Abstract	
W.S.		JP-1998/10317169-A	12-02-1998	McQuarrie et al.	Abstract	
W.S.		JP-1986/61187238-A	08-20-1986	Nobuo et al.	Abstract	
W.S.		JP-1986/61270830-A	12-01-1986	Toru, T.	Abstract	
W.S.		JP-1987/62071217-A	04-01-1987	Toru et al.	Abstract	
W.S.		JP-1988/63155713-A	06-28-1988	Tadashi, F.	Abstract	
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		US-			
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SWJ		JP-1989/01208834-A	08-22-1989	Nobuo et al.	Abstract	
SWJ		JP-1989/10217921-A 01217921-A	08-31-1989	Tsuneo et al.	Abstract	
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OTHER PRIOR ART -- NON PATENT LITERATURE DOCUMENTS			
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S.W.S.		ALIEV et al., "Development of Si(100) Surface Roughness at the Initial Stage of Etching in F <sub>2</sub> and XeF <sub>2</sub> Gases Ellipsometric Study", Surface Science 442 (1999), pp. 206-214.	
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S.W.S.		Kurt Williams, Etch Rates for Micromachining Processing-Part II, 2003 IEEE, Pgs 761-778, Journal of Microelectromechanical Systems, Vol. 12, No. 6, December 2003.	
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		<del>Xenon Difluoride Isotropic Etch System: Seeing is Believing". Surface Technology Systems Ltd. brochure, Newport, UK (date unknown).</del>	
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S.W.S.		BASSOM et al., "Modeling and Optimizing XeF <sub>2</sub> -enhanced FIB Milling of Silicon", 25th International Symposium for Testing and Failure Analysis, Santa Clara, CA (Nov. 14 - 18, 1999), pp. 255-261 (abstract only).	
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S.W.S.		CHANG et al., "Gas-Phase Silicon Micromachining with <sup>Xenon</sup> Xenon Difluoride", Proceedings of the SPIE - The International Society for Optical Engineering, Vol. 2641 (1995), pp. 117-128 (abstract only).	

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8.2.2.8		SEBEL et al., "Reaction Layer Dynamics in Ion-Assisted Si/XeF <sub>2</sub> Etching: Temperature Dependence", J. Vac. Sci. Technol. A, Vac. Surf. Films, Vol. 18, No. 6, (Nov. 2000), pp. 2759-2769 (abstract only).	
8.2.2.8		SEBEL et al., "Silicon Etch Rate Enhancement by Traces of Metal", J. Vac. Sci. Technol. A, Vac. Surf. Films, Vol. 17, No. 3, (May/June 1999), pp. 755-762 (abstract only).	
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		<del>WANG et al., "Gas-Phase Silicon Etching with Bromine Trifluoride", International Solid State Sensors and Actuators Conference (Transducers '97), Chicago, IL, Vol. 2 (June 16 - 19, 1997), pp. 1505-1508 (abstract only).</del>	
8.2.2.8		MUTHUKUMARAN et al., "Gas-Phase Xenon Difluoride Etching of Microsystems Fabricated Through the Mittel 1.5-µm CMOS Process", Can. J. Electr. Comput. Eng. (Canada), Vol. 25, No. 1 (Jan. 2000), pp. 35-41 (abstract only).	
8.2.2.8		TODA et al., "Thin Beam Bulk Micromachining Based on RIE and Xenon Difluoride Silicon Etching", International Solid State Sensors and Actuators Conference (Transducers '97), Chicago, IL, Vol. 1 (June 16 - 19, 1997), pp. 671-674.	
8.2.2.8		SEBEL et al., "Etching of Si Through a Thick Condensed XeF <sub>2</sub> Layer", J. Vac. Sci. Technol. A, Vac. Surf. Films, Vol. 18, No. 5 (Sep/Oct 2000), pp. 2090-2097 (abstract only).	

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			FILING DATE 7/24/03		GROUP <del>Not Yet Assigned</del> 2813		
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
<i>S.W.S.</i>	6,028,690	02/22/00	Carter, et al.				
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
						<input type="checkbox"/>	<input type="checkbox"/>
						<input type="checkbox"/>	<input type="checkbox"/>
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER <i>Stephen W. Smart</i>	DATE CONSIDERED <i>June 20, 2005</i>						

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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THW

Attorney Docket No. P102-US

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of: Patel, et al.

Art Unit: Not Yet Assigned

Serial No.: 10/627,155

Examiner: Not Yet Assigned

Filed: 7/24/03

For: **A MICROMIRROR ARRAY DEVICE WITH SMALL PITCH SIZE**

**INFORMATION DISCLOSURE STATEMENT**  
**PURSUANT TO 37 CFR 1.97(b)**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-145

Sir:

The attention of the Patent and Trademark Office is hereby directed to the following documents:

serial number 10,627,302 to Patel, et al, filed July 24, 2003;

serial number 10,627,303 to Patel, et al, filed July 24, 2003;

The attention of the Patent and Trademark Office is hereby also directed to the documents listed on the attached PTO Form 1449. Copies of the cited references are enclosed.

No fee or certification is required in connection with this Information Disclosure Statement, since it is being submitted prior to the last of (1) issuance of a first official action on the merits and (2) expiration of the three month period following filing of the above-captioned application.

The above information is presented so that the Patent and Trademark Office can determine any materiality thereof to the claimed invention. It is respectfully requested that the information be considered during the prosecution of this application and that the cited documents be listed on the front page of any patent issuing from this application.

Both  
Considered  
S.N.S.  
6-18-05





INFORMATION DISCLOSURE CITATION			ATTY. DOCKET NO.	SERIAL NO.			
PTO-1449			P102-US	10/627,155			
			APPLICANT Patel, et al				
			FILING DATE 7/24/03	GROUP Not Yet Assigned 2813			
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
S.W.S.	2003/0160540	8/28/03	Miller, et al.	—	—		
S.W.S.	6,819,470	11/16/04	Meier, et al.	—	—		
S.W.S.	2003/0117688	6/26/03	Meier, et al.	—	—		
S.W.S.	2003/0117686	6/26/03	DiCarlo	—	—		
S.W.S.	2002/0093721	7/18/02	Knipe	—	—		
	<del>6,724,518</del>	<del>4/20/04</del>	<del>Meyer, et al.</del>	<del>—</del>	<del>—</del>		
S.W.S.	6,147,790	11/14/00	Meier, et al.	—	—		
S.W.S.	6,285,490	9/4/01	Meier, et al.	—	—		
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S.W.S.	2002/0024641	2/28/02	Ilkov, et al.	—	—		
S.W.S.	2004/0004753	1/8/04	Pan	—	—		
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
S.W.S.	WO 2004/001487	12/13/03	PCT	—	—	<input type="checkbox"/>	<input type="checkbox"/>
S.W.S.	WO 2004/000720	12/13/03	PCT	—	—	<input type="checkbox"/>	<input type="checkbox"/>
S.W.S.	WO 2004/001717	12/13/03	PCT	—	—		
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER <u>Stephen W. Smoot</u>	DATE CONSIDERED <u>June 20, 2005</u>						

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.